

RELIABILITY MONITOR

DS1232L APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0105	DE045054ABB	8	SOIC	150x1.4	OSEP
PROCESS Single Poly, Single Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26864	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:		FAIL RATE (Fits): 34	DEVICE HRS: 2.69E+07	
26861	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
26862	STORAGE LIFE MOISTURE SOAK CONVECTION REFLOW	125C	238	24	HOUR	
		85 C/85% R.H.	238	168	HOUR	
		235C	238	3	PASS	0
		TOTAL:				0
26863	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
26865	TEMP CYCLE	-55C TO 125C	40	300	CYCL	1
			39	1000	CYCL	0
		TOTAL:				1
26866	HAST	130C, 85%R.H.,5.5V	77	88	HOUR	0
		TOTAL:				0
26867	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0

PROJECT NO: 17981

RELIABILITY MONITOR

DS1232L APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0105	DE045054ABB	8	SOIC	150x1.4	OSEP
PROCESS Single Poly, Single Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
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TOTAL: 0

JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTIVE ACTION
26865	OPENS	IN PROCESS

RELIABILITY MONITOR

DS1232L JUL '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0105	DK046225ABB	8	SOIC	150x1.4	ATP (Amkor, PI)
PROCESS Single Poly, Single Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27339	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	80	336	HOUR	0
		TOTAL:	98	FAIL RATE (Fits):	DEVICE HRS: 9.39E+06	0
27336	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
27337	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.	241	168	HOUR	
	CONVECTION REFLOW	235C	241	3	PASS	0
		TOTAL:				0
27338	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
27340	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
27341	HAST	130C, 85%R.H.,5.5V	77	100	HOUR	2
		TOTAL:				2
27342	AUTOCLAVE	121C STEAM, UNBIASED	39	96	HOUR	0
		TOTAL:				0

PROJECT NO: 18776

RELIABILITY MONITOR

DS1232L JUL '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0105	DK046225ABB	8	SOIC	150x1.4	ATP (Amkor, PI)
PROCESS Single Poly, Single Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

NO OF

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	FAILS
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JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTIVE ACTION
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27341	1-LEVELS, 1 OPEN	IN VERIFICATION
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PROJECT NO: 18776

RELIABILITY MONITOR

DS1233Z-10 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	0101	DA048537AF	3	SOT223	140x1.7	Fastech
PROCESS Single Poly, Single Metal 1.2 µm Zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26871	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:			FAIL RATE (Fits): 34	DEVICE HRS: 2.69E+07
26868	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
26869	STORAGE LIFE MOISTURE SOAK CONVECTION REFLOW	125C	238	24	HOUR	
		85 C/85% R.H.	238	168	HOUR	
		235C	238	3	PASS	0
		TOTAL:				0
26872	TEMP CYCLE	-55C TO 125C	40	700	CYCL	11
		TOTAL:				11
26873	HAST	130C, 85%R.H.,5.5V	77	100	HOUR	0
		TOTAL:				0
26874	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTIVE ACTION
26872	11-ICC STANDBY	IN VERIFICATION

PROJECT NO: 17982

RELIABILITY MONITOR

DS1233Z-10 JUL '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	0110	DM048543AA	3	SOT223	140x1.7	Carsem
PROCESS Single Poly, Single Metal 1.2 µm Zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27352	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	68	336	HOUR	0
TOTAL:			FAIL RATE (Fits): 115	DEVICE HRS: 7.98E+06		0
27349	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
27350	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.	241	168	HOUR	
	CONVECTION REFLOW	235C	241	3	PASS	0
TOTAL:						0
27353	TEMP CYCLE	-55C TO 125C	40	700	CYCL	0
TOTAL:						0
27354	HAST	130C, 85%R.H.,5.5V	77	100	HOUR	0
TOTAL:						0
27355	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

PROJECT NO: 18777

RELIABILITY MONITOR

DS1233Z-10 OCT '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	0128	DA102602AC	3	SOT223	140x1.7	Fastech
PROCESS Single Poly, Single Metal 1.2 µm Zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
28006	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	68	336	HOUR	0
		TOTAL:	FAIL RATE (Fits): 115	DEVICE HRS: 7.98E+06		0
28003	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
28004	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.	241	168	HOUR	
	CONVECTION REFLOW	235C	241	3	PASS	1
		TOTAL:				1
28007	TEMP CYCLE	-55C TO 125C	40	700	CYCL	0
		TOTAL:				0
28008	HAST	130C, 85%R.H.,5.5V	77	100	HOUR	0
		TOTAL:				0
28009	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0
JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTIVE ACTION				
28004	1-CONTINUITY	IN PROCESS				

PROJECT NO: 19603

RELIABILITY MONITOR

DS1267-010 MAY '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	0104	DK043419AAB	20	TSSOP	4.4x0.9	ATP (Amkor, PI)
PROCESS Single Poly, Single Metal 1.2 µm Implanted Poly 1							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26979	HIGH VOLTAGE LIFE	125C, 6.0 V, -4.0V	75	336	HOUR	0
TOTAL:			283	DEVICE HRS:	3.24E+06	0
26976	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26977	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
26978	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26980	TEMP CYCLE	-55C TO 125C	35	300	CYCL	0
TOTAL:						0
26981	BIASED MOISTURE	85/85, 5.5 VOLTS	75	274	HOUR	0
TOTAL:						0
26982	AUTOCLAVE	121C STEAM, UNBIASED	34	96	HOUR	0
TOTAL:						0

PROJECT NO: 18202

RELIABILITY MONITOR

DS1302 DEC '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1302	A3	0032	DH028629ABD	8	PDIP	300	CPS (ChipPac, China)
PROCESS Single Poly, Double Metal 0.8 μ m Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β :

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26332	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
26333	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
TOTAL:			81	FAIL RATE (Fits): DEVICE HRS: 1.13E+07		0
26334	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
26335	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
26336	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	38	96	HOUR	0
TOTAL:						0

PROJECT NO: 16631

RELIABILITY MONITOR

DS1302 MAR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1302	A3	0105	DH036622AB	8	PDIP	300	CPS (ChipPac, China)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26749	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
26750	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
TOTAL:			81	FAIL RATE (Fits): DEVICE HRS: 1.13E+07		0
26751	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
26752	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
26753	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

PROJECT NO: 17761

RELIABILITY MONITOR

DS1620 MAR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1620	D1	0106	DH045040AAG	8	SOIC	208x1.9	CPS (ChipPac, China)
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26776	INFANT LIFE	125C, 7.0 VOLTS	237	48	HOUR	0
TOTAL:			FAIL RATE (Fits): #Div/0!		DEVICE HRS: 0.00E+00	0
26773	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26774	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.	241	168	HOUR	
	CONVECTION REFLOW	235C	241	3	PASS	0
TOTAL:						0
26775	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26780	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	50	50	KCYC	0
TOTAL:						0
26781	STORAGE LIFE	150C	50	336	HOUR	0
			50	1000	HOUR	0
TOTAL:						0

PROJECT NO: 17781

RELIABILITY MONITOR

DS1620 JUN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1620	D1	0109	DH046190AAI	8	SOIC	208x1.9	CPS (ChipPac, China)
PROCESS		Single Poly, Single Metal 0.8 μm E2PROM process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: Tuse:
Ea: Vuse:
β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27093	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:				0
			FAIL RATE (Fits):	34	DEVICE HRS: 2.69E+07	0
27090	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
27091	STORAGE LIFE MOISTURE SOAK CONVECTION REFLOW	125C	241	24	HOUR	
		85 C/85% R.H.	241	168	HOUR	
		235C	241	3	PASS	0
		TOTAL:				0
27092	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
27094	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
27095	BIASED MOISTURE	85/85, 5.5 VOLTS	70	274	HOUR	1
			69	959	HOUR	0
		TOTAL:				1

PROJECT NO: 18427

RELIABILITY MONITOR

DS1620 JUN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1620	D1	0109	DH046190AAI	8	SOIC	208x1.9	CPS (ChipPac, China)
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27096	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	50	50	KCYC	0
		TOTAL:				0
27097	STORAGE LIFE	150C	50	336	HOUR	0
			50	1000	HOUR	0
		TOTAL:				0
JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTIVE ACTION				
27095	OPENS (VDD)	IN PROCESS				

PROJECT NO: 18427

RELIABILITY MONITOR

DS1620 SEP '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1620	D1	0111	DJ051232AAI	8	SOIC	208x1.9	NSEB
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27859	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	80	336	HOUR	0
		125C, 7.0 VOLTS	80	1000	HOUR	0
		TOTAL:				FAIL RATE (Fits): 33
27856	ULTRASOUND	J-STD-020	4			0
		TOTAL:				
27857	STORAGE LIFE MOISTURE SOAK CONVECTION REFLOW	125C	244	24	HOUR	
		85 C/85% R.H.	244	168	HOUR	
		235C	244	3	PASS	0
		TOTAL:				
27858	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				
27860	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				
27861	BIASED MOISTURE	85/85, 5.5 VOLTS	70	274	HOUR	0
			70	959	HOUR	0
		TOTAL:				

PROJECT NO: 19202

RELIABILITY MONITOR

DS1620 SEP '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1620	D1	0111	DJ051232AAI	8	SOIC	208x1.9	NSEB
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27862	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	50	50	KCYC	0
TOTAL:						0

RELIABILITY MONITOR

DS1803-010 FEB '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0105	DE047362AAB	16	SOIC	150x1.4	OSEP
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26609	INFANT LIFE	125C, 7.0 VOLTS	232	48	HOUR	0
		125C, 7.0 VOLTS	232	48	HOUR	0
26610	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
TOTAL:			15	DEVICE HRS: 6.08E+07		0
26606	ULTRASOUND	J-STD-020	4			0
		TOTAL:				
26607	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
26608	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				
26611	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			34	1000	CYCL	0

PROJECT NO: 17281

RELIABILITY MONITOR

DS1803-010 FEB '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0105	DE047362AAB	16	SOIC	150x1.4	OSEP
PROCESS Single Poly, Double Metal 0.8 μ m Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0
26612	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
		TOTAL:				0
26613	AUTOCLAVE	121C STEAM, UNBIASED	30	96	HOUR	0
		TOTAL:				0

PROJECT NO: 17281

RELIABILITY MONITOR

DS1803-010 MAY '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0115	DM052456ACB	16	SOIC	150x1.4	Carsem
PROCESS Single Poly, Double Metal 0.8 μ m Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: Tuse:
Ea: Vuse:
 β :

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS	
26993	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0	
		125C, 7.0 VOLTS	77	336	HOUR	0	
		125C, 7.0 VOLTS	76	1000	HOUR	0	
		125C, 7.0 VOLTS	76	1000	HOUR	0	
		TOTAL:	18	DEVICE HRS: 5.12E+07		0	
26990	ULTRASOUND	J-STD-020	4			0	
		TOTAL:					0
26991	STORAGE LIFE	125C	238	24	HOUR		
	MOISTURE SOAK	85 C/85% R.H.	238	168	HOUR		
	CONVECTION REFLOW	235C	238	3	PASS	0	
		TOTAL:					0
26994	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0	
			31	1000	CYCL	0	
		TOTAL:					0
26995	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0	
		TOTAL:					0
26996	AUTOCLAVE	121C STEAM, UNBIASED	37	96	HOUR	0	

PROJECT NO: 18204

RELIABILITY MONITOR

DS1803-010 MAY '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0115	DM052456ACB 16	SOIC		150x1.4	Carsem
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

PROJECT NO: 18204

RELIABILITY MONITOR

DS1869 JUN '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	0017	DH833210AAB	8	SOIC	208x1.9	CPS (ChipPac, China)
PROCESS Single Poly, Single Metal 1.2 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25543	INFANT LIFE	125C, 7.0 VOLTS	236	48	HOUR	0
25544	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	76	336	HOUR	0
		125C, 7.0 VOLTS	75	1000	HOUR	0
TOTAL:			30	FAIL RATE (Fits):		0
DEVICES:			3.01E+07			
25540	ULTRASOUND	J-STD-020	4			0
TOTAL:			0			
25541	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.	241	168	HOUR	
	CONVECTION REFLOW	235C	241	3	PASS	0
TOTAL:			0			
25542	PRECONDITION U/S	J-STD-020	4			0
TOTAL:			0			
25545	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:			0			
25546	BIASED MOISTURE	85/85, 5.5 VOLTS	70	274	HOUR	0
			69	959	HOUR	0

PROJECT NO: 14164

RELIABILITY MONITOR

DS1869 JUN '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	0017	DH833210AAB	8	SOIC	208x1.9	CPS (ChipPac, China)
PROCESS Single Poly, Single Metal 1.2 μ m E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β :

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0
25547	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	48	25	KCYC	0
	STORAGE LIFE	150C	46	336	HOUR	0
			46	1000	HOUR	0
TOTAL:						0

PROJECT NO: 14164

RELIABILITY MONITOR

DS2118M JUN '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	B1	0117	DN101149AAD	36	SSOP	7.5x2.4	ATK (Amkor, K)
PROCESS Single Poly, Single Metal 0.6 µm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27114	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		TOTAL:			FAIL RATE (Fits): 93	DEVICE HRS: 9.89E+06
27111	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
27112	STORAGE LIFE MOISTURE SOAK CONVECTION REFLOW	125C	238	24	HOUR	
		60C/60% R.H.	238	40	HOUR	
		235C	238	3	PASS	0
		TOTAL:				0
27113	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
27115	TEMP CYCLE	-55C TO 125C	80	300	CYCL	0
			80	1000	CYCL	0
		TOTAL:				0
27116	AUTOCLAVE	121C STEAM, UNBIASED	77	96	HOUR	0
		TOTAL:				0

PROJECT NO: 18663

RELIABILITY MONITOR

DS21352 JUN '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21352	A4	0103	DN033071AAA	100	LQFP	14x14x	ATP (Amkor, PI)
PROCESS Double Poly, Double Met 0.6 μm Capacitor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: Tuse:
Ea: Vuse:
β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27346	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		TOTAL:			FAIL RATE (Fits): 94	DEVICE HRS: 9.72E+06
27343	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
27344	STORAGE LIFE MOISTURE SOAK CONVECTION REFLOW	125C	238	24	HOUR	
		60C/60% R.H.	238	40	HOUR	
		235C	238	3	PASS	5
		TOTAL:				5
27345	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
27347	TEMP CYCLE	-55C TO 125C	80	300	CYCL	0
			79	1000	CYCL	0
		TOTAL:				0
27348	HAST, NO BIAS	130C, 85% R.H.	62	200	HOUR	0
		TOTAL:				0

PROJECT NO: 18661

RELIABILITY MONITOR

DS21352 JUN '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21352	A4	0103	DN033071AAA	100	LQFP	14x14x	ATP (Amkor, PI)
PROCESS Double Poly, Double Met 0.6 μm Capacitor							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

NO OF

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	FAILS
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JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTIVE ACTION
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27344	5-JITTER TOLERANCE	IN PROCESS
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RELIABILITY MONITOR

DS2154 MAR '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	0106	DN040708AA-1	100	LQFP	14x14x	ATK (Amkor, K)
PROCESS Double Poly, Double Met 0.8 μm Capacitor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26762	INFANT LIFE	125C, 6.0 VOLTS	232	48	HOUR	2
26763	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
TOTAL:			279	FAIL RATE (Fits): DEVICE HRS: 1.11E+07		2
26759	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26760	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	240	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
26761	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26764	TEMP CYCLE	-55C TO 125C	80	300	CYCL	0
			80	1000	CYCL	0
TOTAL:						0
26765	HAST, NO BIAS	130C, 85% R.H.	68	200	HOUR	0
TOTAL:						0

PROJECT NO: 17763

RELIABILITY MONITOR

DS2154 MAR '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	0106	DN040708AA-1	100	LQFP	14x14x	ATK (Amkor, K)
PROCESS Double Poly, Double Met 0.8 μm Capacitor							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

NO OF

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTIVE ACTION				
26762	SIG_CAPB	IN PROCESS				
26762	CONTB	IN PROCESS				

PROJECT NO: 17763

RELIABILITY MONITOR

DS2154 JUN '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	0107	DC040702AA-1	100	LQFP	14x14x	Stats
PROCESS Double Poly, Double Met 0.8 μm Capacitor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27101	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	76	1000	HOUR	0
		TOTAL:			FAIL RATE (Fits): 95	DEVICE HRS: 9.68E+06
27098	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
27099	STORAGE LIFE MOISTURE SOAK CONVECTION REFLOW	125C	238	24	HOUR	
		60C/60% R.H.	238	40	HOUR	
		235C	238	3	PASS	0
		TOTAL:				0
27100	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
27102	TEMP CYCLE	-55C TO 125C	80	300	CYCL	0
			80	1000	CYCL	0
		TOTAL:				0
27103	HAST, NO BIAS	130C, 85% R.H.	76	200	HOUR	0
		TOTAL:				0

PROJECT NO: 18642

RELIABILITY MONITOR

DS2154 SEP '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	0125	DN104641AA-1	100	LQFP	14x14x	ATK (Amkor, K)
PROCESS Double Poly, Double Met 0.8 μ m Capacitor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27841	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	80	336	HOUR	0
		TOTAL:	265	FAIL RATE (Fits):	DEVICE HRS: 3.45E+06	0
27838	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
27839	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	60C/60% R.H.	241	40	HOUR	
	CONVECTION REFLOW	235C	241	3	PASS	0
		TOTAL:				0
27840	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
27842	TEMP CYCLE	-55C TO 125C	80	300	CYCL	0
		TOTAL:				0
27843	HAST, NO BIAS	130C, 85% R.H.	77	200	HOUR	0
		TOTAL:				0

PROJECT NO: 19201

RELIABILITY MONITOR

DS2175 JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2175	D1	0046	DE033119AAB	16	SOIC	300x2.3	ATP (Amkor, PI)
PROCESS Single Poly, Single Metal 2.0 µm Pfield							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26422	INFANT LIFE	125C, 7.0 VOLTS	233	48	HOUR	0
26423	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
TOTAL:			30	FAIL RATE (Fits):		0
			DEVICE HRS: 3.08E+07			
26419	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26420	TEMP CYCLE	-55C TO 125C	238	10	CYCL	
	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
26421	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26424	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
26425	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0

PROJECT NO: 16724

RELIABILITY MONITOR

DS2175 JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2175	D1	0046	DE033119AAB	16	SOIC	300x2.3	ATP (Amkor, PI)
PROCESS Single Poly, Single Metal 2.0 μm Pfield							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0
26426	AUTOCLAVE	121C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

PROJECT NO: 16724

RELIABILITY MONITOR

DS2175 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2175	D1	0050	DK036683ABD	16	SOIC	300x2.3	ATP (Amkor, PI)
PROCESS		Single Poly, Single Metal		2.0 μ m	Pfield		

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26883	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:			FAIL RATE (Fits): 34	DEVICE HRS: 2.69E+07
26880	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
26881	TEMP CYCLE	-55C TO 125C	238	10	CYCL	
	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:					0	
26882	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
26884	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
26885	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
		TOTAL:				0

PROJECT NO: 18002

RELIABILITY MONITOR

DS2175 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH ASSEMBLY SITE
DS2175	D1	0050	DK036683ABD	16	SOIC	300x2.3 ATP (Amkor, PI)
PROCESS Single Poly, Single Metal 2.0 μ m Pfield						

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26886	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS21Q43A DEC '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21Q43	A3-A	0034	DN027568AAC	128	LQFP	14x20x	ATK (Amkor, K)
PROCESS Single Poly, Single Metal 0.6 µm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26369	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
26370	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	76	336	HOUR	0
		125C, 6.0 VOLTS	76	1000	HOUR	0
TOTAL:			90	FAIL RATE (Fits): DEVICE HRS: 1.02E+07		0
26366	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26367	STORAGE LIFE	125C	239	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	239	240	HOUR	
	CONVECTION REFLOW	235C	239	3	PASS	0
TOTAL:						0
26368	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26371	TEMP CYCLE	-55C TO 125C	70	300	CYCL	0
			70	1000	CYCL	0
TOTAL:						0
26372	BIASED MOISTURE	85/85, 5.5 VOLTS	31	274	HOUR	0
			31	959	HOUR	0

PROJECT NO: 16633

RELIABILITY MONITOR

DS21Q43A DEC '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21Q43	A3-A	0034	DN027568AAC	128	LQFP	14x20x	ATK (Amkor, K)
PROCESS Single Poly, Single Metal 0.6 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0
26373	HAST, NO BIAS	130C, 85% R.H.	36	100	HOUR	0
		TOTAL:				0

PROJECT NO: 16633

RELIABILITY MONITOR

DS21Q43A SEP '01 MONITOR, D.P.

DEVICE	REVISIO	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21Q43	A3-A	0047	DC036714AAD	128	LQFP	14x20x	Stats

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27877	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
27878	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	60C/60% R.H.	241	40	HOUR	
	CONVECTION REFLOW	235C	241	3	PASS	0
		TOTAL:				0

PROJECT NO: 19205

RELIABILITY MONITOR

DS21S07 FEB '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21S07	C1-A	0047	DM035532AFD	20	TSSOP	4.4x0.9	Carsem
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS	
26588	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0	
		125C, 7.0 VOLTS	77	1000	HOUR	0	
		TOTAL:				FAIL RATE (Fits): 37	DEVICE HRS: 2.50E+07
26584	ULTRASOUND	J-STD-020	4			0	
		TOTAL:					0
26585	STORAGE LIFE MOISTURE SOAK CONVECTION REFLOW	125C	238	24	HOUR		
		85 C/85% R.H.	238	168	HOUR		
		235C	238	3	PASS		0
		TOTAL:					0
26586	PRECONDITION U/S	J-STD-020	4			0	
		TOTAL:					0
26589	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0	
			40	1000	CYCL	0	
		TOTAL:					0
26590	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0	
			77	959	HOUR	0	
		TOTAL:					0

PROJECT NO: 17101

RELIABILITY MONITOR

DS21S07 FEB '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21S07	C1-A	0047	DM035532AFD	20	TSSOP	4.4x0.9	Carsem
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26591	AUTOCLAVE	121C STEAM, UNBIASED	36	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS2401 SEP '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2401	C2	0130	DA033008AJ	3	TO92	150	Fastech
PROCESS Single Poly, Single Metal 0.6 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27884	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	80	336	HOUR	0
		125C, 6.0 VOLTS	80	1000	HOUR	0
		TOTAL:		89	DEVICE HRS: 1.03E+07	
27885	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				
27886	HAST	130C, 85%R.H.,5.5V	77	100	HOUR	0
		TOTAL:				
27887	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				

PROJECT NO: 19206

RELIABILITY MONITOR

DS2502 APR '01 MONITOR

DEVICE	REVISIO	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C4	0107	DE041143AKA	6	TSOC	150x1.2	OSEP

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26914	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
26915	STORAGE LIFE	125C	151	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.	151	168	HOUR	
	CONVECTION REFLOW	235C	151	3	PASS	0
		TOTAL:				0
26916	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
26917	TEMP CYCLE	-55C TO 125C	77	300	CYCL	0
		-55C TO 125C	77	1000	CYCL	0
		TOTAL:				0
26918	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	70	96	HOUR	0
		TOTAL:				0

PROJECT NO: 18042

RELIABILITY MONITOR

DS2502 JUL '01 MONITOR

DEVICE	REVISIO	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C4	0125	DE052527ACA	6	TSOC	150x1.2	OSEP

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27372	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
27373	STORAGE LIFE	125C	151	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.	151	168	HOUR	
	CONVECTION REFLOW	235C	151	3	PASS	0
		TOTAL:				0
27374	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
27375	TEMP CYCLE	-55C TO 125C	77	300	CYCL	0
		-55C TO 125C	77	1000	CYCL	0
		TOTAL:				0
27376	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	70	96	HOUR	0
		TOTAL:				0

PROJECT NO: 18780

RELIABILITY MONITOR

DS5002 JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0047	DN028766AAD	80	MQFP	14x20x	ATK (Amkor, K)
PROCESS Single Poly, Single Metal 0.6 μm Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26508	INFANT LIFE	125C, 6.0 VOLTS	198	48	HOUR	0
26509	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
TOTAL:			83	FAIL RATE (Fits): DEVICE HRS: 1.11E+07		0
26505	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26506	STORAGE LIFE	125C	203	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	203	144	HOUR	
	VAPOR PHASE REFLOW	220C	203	3	PASS	0
TOTAL:						0
26507	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26510	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
26511	BIASED MOISTURE	85/85, 5.5 VOLTS	42	274	HOUR	0
			41	959	HOUR	0

PROJECT NO: 16727

RELIABILITY MONITOR

DS5002 JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0047	DN028766AAD	80	MQFP	14x20x	ATK (Amkor, K)
PROCESS Single Poly, Single Metal 0.6 μm Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0
26512	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	37	96	HOUR	0
		TOTAL:				0

PROJECT NO: 16727

RELIABILITY MONITOR

DS5002 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0112	DN030363AAA	80	MQFP	14x20x	ATK (Amkor, K)
PROCESS		Single Poly, Single Metal 0.6 µm Buried contacts w/silicided poly					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: Tuse:
Ea: Vuse:
β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26901	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		TOTAL:		FAIL RATE (Fits): 94	DEVICE HRS: 9.72E+06	
26898	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
26899	STORAGE LIFE MOISTURE SOAK VAPOR PHASE REFLOW	125C	203	24	HOUR	
		30C/60% R.H.	203	144	HOUR	
		220C	203	3	PASS	0
		TOTAL:				0
26900	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
26902	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
26903	BIASED MOISTURE	85/85, 5.5 VOLTS	42	274	HOUR	0
			42	959	HOUR	0
		TOTAL:				0

PROJECT NO: 18041

RELIABILITY MONITOR

DS5002 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0112	DN030363AAA	80	MQFP	14x20x	ATK (Amkor, K)
PROCESS Single Poly, Single Metal 0.6 μ m Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26904	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS5002 JUL '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C6	0122	DN042297AAA	80	MQFP	14x20x	ATK (Amkor, K)
PROCESS Single Poly, Single Metal 0.6 μm Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27364	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	80	336	HOUR	0
		125C, 6.0 VOLTS	80	1000	HOUR	0
		TOTAL:			FAIL RATE (Fits): 89	DEVICE HRS: 1.03E+07
27361	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
27362	STORAGE LIFE MOISTURE SOAK CONVECTION REFLOW	125C	206	24	HOUR	
		60C/60% R.H.	206	40	HOUR	
		220C	206	3	PASS	0
		TOTAL:				0
27363	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
27365	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
27366	BIASED MOISTURE	85/85, 5.5 VOLTS	42	274	HOUR	0
			41	959	HOUR	0
		TOTAL:				0

PROJECT NO: 18779

RELIABILITY MONITOR

DS5002 JUL '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C6	0122	DN042297AAA	80	MQFP	14x20x	ATK (Amkor, K)
PROCESS Single Poly, Single Metal 0.6 μ m Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27367	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS80CH11 MAR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80CH11	A4	0103	DN029182AAA	128	LQFP	14x20x	ATK (Amkor, K)
PROCESS Single Poly, Double Metal 0.6 µm PolySilicide							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26786	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
27058	INFANT LIFE	125C, 6.0 VOLTS	235	48	HOUR	0
TOTAL:			199	FAIL RATE (Fits): DEVICE HRS: 4.60E+06		0
26782	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26783	STORAGE LIFE	125C	239	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	239	240	HOUR	
	CONVECTION REFLOW	235C	239	3	PASS	
TOTAL:						
26784	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26787	TEMP CYCLE	-55C TO 125C	70	300	CYCL	0
TOTAL:						0
26788	BIASED MOISTURE	85/85, 5.5 VOLTS	48	274	HOUR	0
			45	959	HOUR	0
TOTAL:						0
26789	HAST, NO BIAS	130C, 85% R.H.	40	100	HOUR	0

PROJECT NO: 17782

RELIABILITY MONITOR

DS80CH11 MAR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80CH11	A4	0103	DN029182AAA	128	LQFP	14x20x	ATK (Amkor, K)
PROCESS Single Poly, Double Metal 0.6 μ m PolySilicide							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

NO OF

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
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TOTAL:	0
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PROJECT NO: 17782

RELIABILITY MONITOR

DS80CH11 JUN '01 MONITOR

DEVICE	REVISIO	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80CH11	A4	0108	DN034351AA	128	LQFP	14x20x	ATK (Amkor, K)

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27104	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
27105	STORAGE LIFE	125C	239	24	HOUR	
	MOISTURE SOAK	60C/60% R.H.	239	40	HOUR	
	CONVECTION REFLOW	235C	239	3	PASS	0
		TOTAL:				0

PROJECT NO: 18662

RELIABILITY MONITOR

DS80CH11 SEP '01 MONITOR

DEVICE	REVISIO	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80CH11	A4	0110	DC037148AA	128	LQFP	14x20x	Stats

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27864	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
27865	STORAGE LIFE	125C	242	24	HOUR	
	MOISTURE SOAK	60C/60% R.H.	242	40	HOUR	
	CONVECTION REFLOW	235C	242	3	PASS	0
		TOTAL:				0

PROJECT NO: 19203